

Surface Scanning Laser Confocal Displacement Meter LT-9000 Series



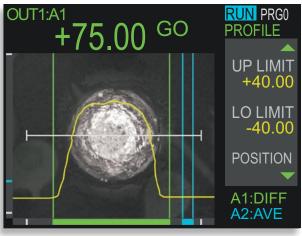
High-Accuracy Surface Scanning Method

High resolution of 0.01 µm



The high-accuracy, surface scanning method allows measurements of all types of targets

A tuning fork and oscillator unit are combined to create a surface scanning laser. This results in precise displacement and profile measurements that are unaffected by target color or angle.

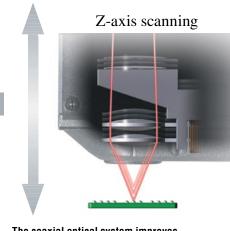


Surface Scanning Laser Confocal Displacement Meter LT-9000 Series

BGA profile measurement



Excellent resolution of 0.01 μ m for high-accuracy applications



The coaxial optical system improves measurement performance

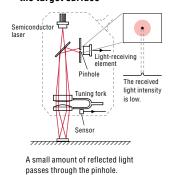


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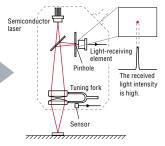
High-accuracy measurement method uses the confocal principle and tuning fork

The laser beam is focused on the target surface through an objective lens that vibrates up and down at high speed by means of a tuning fork. The beam reflected off the target surface is converged on a pinhole and then enters the light-receiving element. By measuring the exact position of the objective lens when the light enters the light-receiving element, the target height can be determined. The sensor measures the distance to the target surface accurately without being affected by the material, color, or angle of the target.

When focus is not obtained on the target surface

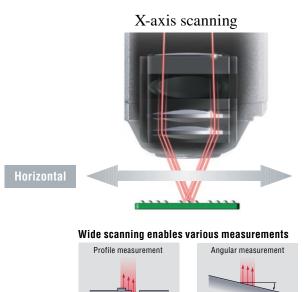


When focus is obtained on the target surface



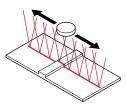
All of the reflected light passes through the pinhole.

New wide scanning feature increases measurement stability and versatility



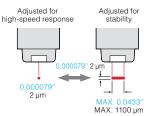
High-accuracy scanning using an oscillator unit

The 0.000079" 2 µm laser beam spot can be scanned horizontally for up to 0.043307" 1100 µm by using the high-accuracy oscillating mechanism. This new scanning method enables measurements of profile, angle, and area.



Adjustable scanning width according to the application

The scanning width of the laser beam can be changed freely according to the application and the surface condition of the target. In addition, highly stable displacement measurements are ensured by calculating the scanning data.



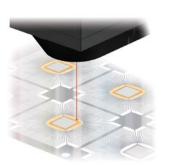
A variety of high accuracy measurements are possible.

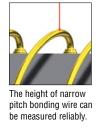
Typical applications for the LT-9000 Series

Microscopic targets

A small spot size enables the measurement of microscopic features.

Measuring the height of bonding wire





Measuring the score depth of a pull-tab

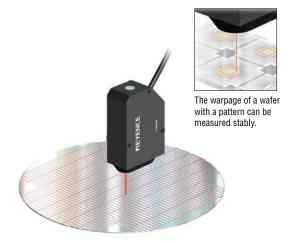


The depth and profile of the groove can be measured stably.

Rough-surfaced targets

The light intensity integration function and laser scanning method offer high stability.

Measuring warpage of a wafer





When the laser scanning method is disabled:

The measurement is affected by the pattern on the surface.

The measurement value is unstable due to the influence of the surface conditions.

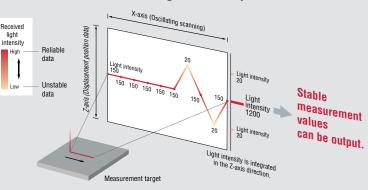
When the laser scanning method is enabled:

Accurate measurement is obtained by eliminating the influence of the pattern.

The measurement value is stable, enabling the measurement of the warpage profile.

The light intensity integration function — Provides high stability

- 1. The 0.000079" 2 μm beam spot is shifted in the X-axis direction with the movement of the oscillator unit.
- The data of each spot in the X-axis direction is divided into two categories: the displacement position data (Z-axis) and the light intensity data.
- 3. Data is obtained from the rough surface of the target, in which stable data with high received light intensity and unstable data with low received light intensity are mixed. The light intensity integration function further enhances the difference of the light intensity by integrating the light intensity of the Z-axis direction, and it outputs stable displacement position data unaffected by the unstable data with low received light intensity.



UP LIMIT

POSITION



Multiple measurement modes for a wide range of applications

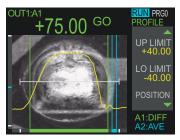
Profile measurement

The surface profile can be traced accurately using the oscillating unit.

Measuring the profile of solder paste on a PWB

The surface profile can be traced using the double-scanning method. The height difference between the two points can be measured.

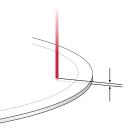




The profile of lead-free solder can be measured for detecting abnormalities such as cracks, bridges, and insufficient soldering.

The surface condition, film thickness, and thickness of transparent objects can be measured stably by utilizing the confocal principle.

Transparent object thickness measurement



The surface condition, film thickness, and thickness of transparent objects can be measured. In addition, the **slant correction function** enables more reliable measurements.

Measuring the thickness of an optical disc



The intermediate layer of an optical disc can be measured.



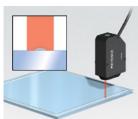
Multi-surface measurement function

The peak value of light intensity of up to four points can be detected with one measurement unit. The selected measurement surface can be measured with high accuracy.

1	 The first surface
	 The second surface
-	 The third surface
	- The fourth surface

Measurement of a cross-sectional area

Measuring the cross-sectional area of liquid sealing material



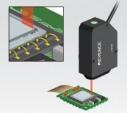
The profile and cross-sectional area of sealing material applied for bonding glass substrates.

Angle measurement

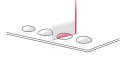


An angle can be measured in increments of 0.01 degrees based on the measurement values of two or more points obtained by scanning the laser beam spot.

Measuring the parallelism of a CCD and cover glass



The inclination of a CCD surface against the rear surface of the glass can be measured accurately using the newly developed relative angle measurement.



The cross-sectional area can be determined based on the cross sectional profile obtained by scanning the laser beam spot.

Quick and easy setup functions

Microscope function _____ Employing a high-speed auto-focus lens for clear images

An ultra-compact CCD camera is incorporated in the sensor head. The target image can be enlarged approximately 85 times* on the monitor screen. The special optical design provides sharp images, allowing easy positioning of microscopic targets.

* When using special monitor CA-MN81

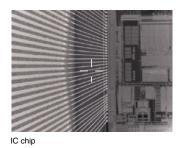




Image of phoenix on a 10-yen coin

Monitor for measured value and waveform display -For real-time display of measured values and waveform

Observations of displacement and profile data can be performed with ease.





Soldered area of leads

Engraved mark

Simplified setup menu — Simple operation using special remote console

The special remote console and user-friendly setup menu greatly simplify the setup process. Measurement can begin just minutes after unpacking the box.



Multiple I/O options come standard –

—— For enhanced operational flexibility

All of the necessary interfaces including 2 channels of analog outputs, RS-232C output, 2 channels of decision outputs, and binary outputs are incorporated as standard into the compact housing.

(Only half the size of conventional models.)



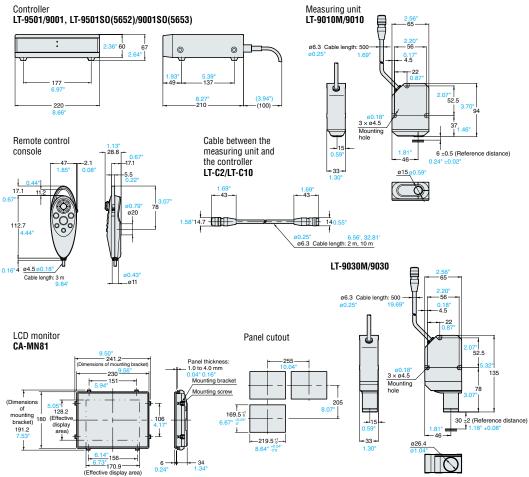
2-channel decision output and binary output



System configuration



Dimensions



New features of the LT-9000 Series

Interchangeable sensor head and controller

A CPU is built into the sensor head so that the sensor head and controller become interchangeable. The calibration data and other information of the sensor head is digitally transferred to the controller. Complicated adjustments are no longer required upon replacement.

Calibration function

The measured values can be calibrated by using a reference target. Since logical calibration can be performed using numerical values, optimal adjustment can be made according to the details of the actual target measurements.

Up to 65.6' 20 m cable extension

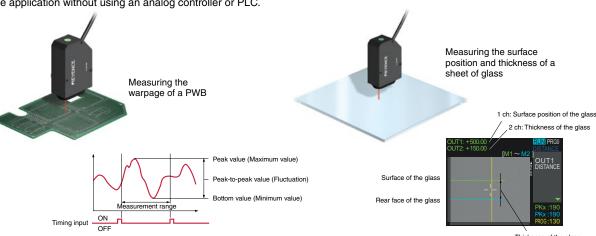
Wiring can be extended up to 65.6' 20 m by adopting the digital method for communications between the controller and sensor head. This greatly enhances the installation flexibility.

Various measurement modes

The LT-9000 Series features 9 types of measurement hold modes, including Peak hold, Bottom hold, and Peak-to-peak hold mode. The mode can be set up as desired according to the application without using an analog controller or PLC.

2-channel simultaneous measurement

The measurement of two different points can be performed simultaneously. The surface position and thickness of glass can be measured and displayed at the same time.



Thickness of the glass

Applications by industry

Automotive industry



Measuring the surface profile of a brake disc

LCD industry



Measuring the cross-sectional area of liquid sealing material on LCD glass

Print industry



Measuring the cell depth of a print roll

Medical industry



Measuring the thickness of a contact lens

Specifications

Controller

	A. A			LT-9501SO(5652)/LT-9001SO(5653)	
Monouring unit (weasuring unit		LT-9010M/LT-9010	LT-9030M/LT-9030	
weasuring unit u	compatibility		Measuring units are interchangea	ble without factory recalibration.	
	Minimum display	/ unit	0.01 μm, 1 μm ² , 0.01°	0.01 µm	
Model Measuring unit LT-9010M/LT-9010 LT-9030M/L Measuring unit compatibility Measuring units are interchangeable without factory recalibration of the measuring units are interchangeable without factory recalibration of the measuring units are interchangeable without factory recalibration of the measuring units are interchangeable without factory recalibration of the measuring units are interchangeable without factory recalibration of the measurement of the measurement, Partage and the measurement, Parta	Display range		±9999.99 μm, ±999999 μm ² , ±9999.99°	±9999.99 μm	
	Available (LT-9501SO(5652) only)				
	Display cycle ^{1.}		10 tim	es/sec.	
Tennelinel	Analog output				
			Non-voltage input		
biook	Monitor dedicate	d power supply ^{2.}	24 VDC, 1 A		
	Limits mode ^{3.}	3-step limits output	For OUT1 and OUT2, and I	NPN open collector output	
Control I/O Contro	Binary output	Measured data output (21 bits), OUT1/OUT2/PROFILE selectable NPN open collector output			
	Binary mode ^{3.}	Strobe output	NPN open collector output		
Control I/O		Binary selection output	NPN open collector output		
		Binary selection input	Non-volta	age input	
			NPN open co	llector output	
	Laser remote input		Non-voltage input		
	Program change input		Non-voltage input × 3 inputs		
			Measured data output and control I/O (Selectable up to baud rate 115200 bps)		
Video output			NTSC compliant (PIN connector)		
	Distance mode ^{4.}		measurement, Angle measurement, Relative angle measurement, Surface selection, Dark-out, Mask,	Distance measurement, Transparent object thickness measurement, Surface selection, Dark-out, Mask, Trend graph display, and Scan width/interval change	
	Profile mode ^{4.}		Maximum-to-minimum, Area) Area calculation, Scan width/interval change, Dark-out, Smoothing,	-	
	Common		Light intensity accumulation, Microscope (LT-9501, LT-9501SO(5652) only), Tolerance judgment, 8-program registration, Calibration, Averaging, Hold modes, Auto-zero, and interface language selection		
	Power supply voltage		100 to 240 VAC±10% 50/60 Hz		
Pating	Current consumption		110 VA or lower		
naully	Overvoltage category		I		
	Pollution degree		2		
Ambient temperature			0 to 35°C 32 to 95°F, No condensation		
Relative humidity			35 to 85%, No condensation		
Weight			Approx. 2.4 kg		

1. Varies depending on the setting
2. Dedicated power supply for the monitor specified by KEYENCE.
3. Select either the Limits mode or the Binary mode.
4. Select either the Distance mode or the Profile mode.
4. Select either the Distance mode or the Profile mode.
The rating of the NPN open-collector output is 30 mA (30 V or lower) maximum, and residual voltage is 0.5 V.
The rating of the Non-voltage input is ON voltage 1 V or lower, and OFF current 0.6 mA or lower.

Cable between the sensor head and controller (Extension cable)

Model	LT-C2	LT-C10
Cable length	6.56' 2 m	32.81' 10 m
Weight	Approx. 200 g	Approx. 700 g

* Up to 3 cables can be connected with a total maximum length of 65.6' 20 m.

Measuring Unit

Туре		High-ad	curacy				
Model		LT-9010M	LT-9010	LT-9030M LT-9030			
Measurement ra	inge	±0.01" ±0.3 mm		±0.04" ±1.0 mm			
Reference dista	се	0.20" 6 mm		1.18" 30 mm			
		Visible red semiconductor laser					
	Wavelength		655	inm			
ight source	Output		170 µW (IEC).	/3.0 μW (FDA)			
	Laser Class	Class	IIa (FDA CDRH 21CFR Part	1040.10), Class 1 (IEC60825-1)			
	trange ±0.01" ±0.3 mm ±0.04 distance 0.20° 6 mm 1.18 Visible red semiconductor laser 0.20° 6 mm 655 nm Output 170 µW (IEC)/3.0 µW (FDA) Laser Class Class IIa (FDA CDRH 21CFR Part 1040.10), Class 1 (IEC6 Spot diameter Approx. 90.000079" 92 µm Approx. 90.000079" 92 µm h/interval 0 to 0.0433" 0 to 1100 µm (6 steps)/ 0 to 0.0220" 01 0.000039 to 0.00039 to 0.00039 to 1100 µm (6 steps) 0.000039 to 0.000039 to 0.000039 to 0.0000039 to 0.0000039 to 0.0000000000000000000000000000000000	000276" ø7 μm					
Scan width/inte	rval			0 to 0.0220° 0 to 560 μm (6 steps)/ 0.000039 to 0.000315° 1 to 8 μm (4 steps)			
Resolution ^{1.}		0.01 µm		0.000004" 0.1 μm		0.000004" 0.1 μm	
Linearity ^{1.}		±0.5% of F.S.		±0.3% of F.S.		±0.3% of F.S.	
Sampling cycle		640 µs to 356 ms (14 steps) ^{2.}		640 µs to 187 ms (14 steps) ^{3.}			
		±0.5% of F.S.		±0.25% of F.S.			
		Available	Unavailable	Available	Unavailable		
Sampling cycle Temperature chara (20 to 30°C 68 to Microscope function	Field of view		-		-		
	Illumination light source		-	Infrared LED (wavelength: 870 nm)	-		
Ambient light			Incandescent lamp/fluores				
Ambient temperature 0 to 35°C 32 to 95°F, No conder		F, No condensation					
Relative humidity		35 to 85%, No condensation					
Weight		Approx	. 400 g	Approx. 500 g			

1. The value when the measurement target is an mirrored surface object that is measured in displacement mode, scan width/interval 0.004724" 120 μm/0.000079" 2 μm, and 8-times average 2. The value when the FINE mode is set to OFF. 3. Sampling cycle differs according to the manufacturing variation of individual measuring units.

CE

www.keyence.com/measure/

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SAFETY INFORMATION Please read the instruction manual carefully in order to safely operate any KEYENCE product.

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